

Keysight Technologies Malaysia Sdn Bhd (463532-M) Bayan Lepas Free Industrial Zone 11900 Penang, Malaysia



# **Certificate of Calibration**

ANSI/NCSL Z540-1-1994

Certificate No: PENANG4397681-5379192-1

Manufacturer: Keysight Technologies **Description:** Nano Volt/Micro Ohm Meter

**Model No: 34420A** Serial No: MY42009500

Options Installed With Specifications: N/A

Date of Calibration: 05-MAR-2020

Temperature: (23 ± 2) °C Humidity: (30 to 70)% RH

Procedure: 34420A.CAL.N76

This certifies that the equipment has been calibrated using applicable Keysight Technologies procedures and in compliance with ISO/IEC 17025:2017 and ANSI/NCSL Z540-1-1994. The quality management system is registered to ISO 9001:2015.

As Received Conditions: Factory tested. No incoming data available.

#### **Action Taken:**

No corrective actions were necessary.

As Shipped Conditions: At the completion of the calibration, measured values were IN SPECIFICATION at the points tested.

#### Remarks or special requirements:

This calibration includes the attached measurement report with report number 2007A55173.

#### Notes:

- 1. This calibration report may refer to equipment manufactured by HP, Agilent and Keysight as being manufactured by Keysight Technologies, Inc.
- 2. The test limits stated in the calibration report correspond to the published specifications of the equipment, at the points tested.
- 3. The documented test results relate to the equipment tested only.
- 4. This calibration report shall not be reproduced, except in full

Traceability Information: Measurements are traceable to the International System of Units (SI) via national metrology institutes (www.keysight.com/find/NMI) that are signatories to the CIPM Mutual Recognition Arrangement.

#### **Uncertainty of Measurement**

The uncertainty evaluation has been performed in accordance with ISO/IEC Guide 98-3:2008 (GUM). The reported expanded uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k such that the coverage probability corresponds to approximately 95 %. This probability corresponds to a coverage factor of k=2 for a normal distribution.

Print Date: 05-MAR-2020

Tay Eng Su **Quality Manager** 

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**Certificate of Calibration** 

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Certificate No: PENANG4397681-5379192-1

Calibration Equ	uipment Used	Date Used: Date equ	ipment used in	this calibration
<b>Model Number</b>	Model Description	Equipment ID	<b>Date Used</b>	Cal Due Date
FLU 742A-10	Resistance Standard	PZ00061	05-MAR-2020	24-OCT-2020
FLU 742A-1	Resistance Standard	PZ00060	05-MAR-2020	24-OCT-2020
FLU 742A-100K	Resistance Standard	PZ00063	05-MAR-2020	26-OCT-2020
FLU 742A-100	Resistance Standard	PZ00062	05-MAR-2020	26-OCT-2020
FLU 5720A	Calibrator	PZ00034	05-MAR-2020	24-MAY-2020

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# Measurement Report

Keysight Technologies Malaysia Sdn Bhd (463532-M)
Bayan Lepas Free Industrial Zone
11900, Penang
Malaysia

Report Number: 2007A55173 Customer:

Model Number: 34420A Serial Number: MY42009500

Tested Options:

**Test Date:** 5 Mar 2020 **Tested By:** N1008234

**Temperature:** (23.0±2) °C **Humidity:** (30 to 70)% RH

Test Program Name: HP34420A Part No. 5011-4052

Test Program Version: C.02.04

Test Executive: STE/9000 C.09.05W (MENDOR B.06.34)

## Specification Limits:

Unless indicated otherwise, the units for minimum and/or maximum specification limits are the same as the units stated for the measured value.

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## Measurement Report

 Report Number:
 2007A55173
 Test Date:
 5 Mar 2020

 Model Number:
 34420A
 Serial Number:
 MY42009500

## Result Status Flags:

Each measurement result stated will contain a result status flag.

The status flags are defined as follows:

- ' ' Passed. The measured values of the equipment were observed in specification at the points tested.

  Additionally, the expanded measurement uncertainty intervals about the measured values were in specification.
- 'P‡' Passed‡. The measured values of the equipment were observed in specification at the points tested.

  However, a portion of the expanded measurement uncertainty intervals about one or more measured values exceeded specification. Consequently, compliance with specification cannot be declared based on the stated coverage probability.
- 'F‡' Failed‡. One or more measured values of the equipment were observed out of specification at the points tested. However, a portion of the expanded measurement uncertainty intervals about one or more measured values were in specification. Consequently, non-compliance with specification cannot be declared based on the stated coverage probability.
- 'F' Failed. One or more measured values of the equipment were observed out of specification at the points tested. Additionally, the expanded measurement uncertainty intervals about one or more measured values were entirely outside the specification.

### Calibration Standards Used

<u>Model No.</u>	<u>Serial No.</u>	Asset No.	<u> Cal Due Date</u>
FLU5720A	7660210	PZ00034	24 May 2020
FLUKE 742A-100K	7944003	PZ00063	26 Oct 2020
FLUKE 742A-100	7950004	PZ00062	26 Oct 2020
FLUKE 742A-10	7955002	PZ00061	24 Oct 2020
FLUKE 742A-1	8004006	PZ00060	24 Oct 2020

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## PERFORMANCE TEST RESULTS SUMMARY

<u> Test Name</u>	<u>Status</u>
INITIAL SETUP	DONE
ZERO OFFSET	PASSED
DC VOLTAGE GAIN	PASSED
OHMS GAIN	PASSED

ZERO OFFSET PASSED

TEST CONDI	TIONS	MINIMUM	MEASURED	MAXIMUM	UNCERT.
Range	Input				
DC Voltage	Channe	:11			
1 mV 0 10 mV 0 100 mV 0 1 V 0 10 V 0	V V V	-120.0 -0.130 -0.40 -4.0 -0.040 -0.50	-0.6 nV -0.002 μV 0.01 μV -0.1 μV 0.000 mV 0.00 mV	0.130 0.40 4.0 0.040	53 nV 50 nV 50 nV 0.23 μV 1.0 μV 25 μV
DC Voltage	Channe	:12			
1 mV 0 10 mV 0 100 mV 0 1 V 0 10 V 0	V V V	-120.0 -0.130 -0.40 -4.0 -0.040	5.5 nV 0.005 μV -0.01 μV -0.4 μV 0.000 mV	0.130 0.40 4.0	53 nV 50 nV 50 nV 0.28 μV 0.48 μV
4-Wire Ohm	ıs				
1 Ω 0 Ω 10 Ω 0 Ω 100 Ω 0 Ω 1 kΩ 0 Ω 10 kΩ 0 Ω 100 kΩ 0 Ω 1 MΩ 0 Ω	2 2 2	$     \begin{array}{r}       -2.0 \\       -0.020 \\       -0.20 \\       -2.0 \\       -0.020 \\       -0.40 \\       -4.0 \\    \end{array} $	$\begin{array}{cccc} -0.8 & \mu\Omega \\ 0.005 & m\Omega \\ -0.01 & m\Omega \\ -0.2 & m\Omega \\ 0.002 & \Omega \\ -0.01 & \Omega \\ -0.2 & \Omega \end{array}$	2.0 0.020 0.20 2.0 0.020 0.40 4.0	$\begin{array}{c} 0.47 \;\; \mu\Omega \\ 3.3 \;\; \mu\Omega \\ 33 \;\; \mu\Omega \\ 0.28 \;\; m\Omega \\ 1.8 \;\; m\Omega \\ 14 \;\; m\Omega \\ 0.14 \;\; \Omega \end{array}$
Low Power	Ohms				
1 Ω 0 Ω 10 Ω 0 Ω 100 Ω 0 Ω 1 kΩ 0 Ω 10 kΩ 0 Ω 100 kΩ 0 Ω 1 MΩ 0 Ω	2 2 2	$     \begin{array}{r}       -2.0 \\       -0.020 \\       -0.20 \\       -2.0 \\       -0.040 \\       -1.50 \\       -4.0 \\    \end{array} $	$\begin{array}{cccc} -0.6 & \mu\Omega \\ 0.004 & m\Omega \\ -0.04 & m\Omega \\ 0.0 & m\Omega \\ -0.001 & \Omega \\ -0.04 & \Omega \\ -0.2 & \Omega \end{array}$	2.0 0.020 0.20 2.0 0.040 1.50 4.0	0.55 μΩ 3.3 μΩ 18 μΩ 0.28 mΩ 7.1 mΩ 33 mΩ 0.23 Ω
Voltage Li	mited O	hms			
10 Ω 0 Ω		-0.020 -0.20	$\begin{array}{c} \text{0.006 } \text{m}\Omega \\ \text{0.06 } \text{m}\Omega \end{array}$	0.020	3.3 μΩ 33 μΩ
2-Wire Ohm	ıs				
1 Ω 0 Ω 10 Ω 0 Ω		-200002.0 -200.020	$\begin{array}{cccc} 27143.1 & \mu\Omega \\ 26.440 & \text{m}\Omega \end{array}$	200002.0 200.020	$\begin{array}{ccc} \text{0.22} & \text{m}\Omega \\ \text{0.12} & \text{m}\Omega \end{array}$

ZERO OFFSET	CONTINUED
ZERO OFFDEI	CONTINUED

TEST CONDITIONS	MINIMUM	MEASURED	MAXIMUM	UNCERT.
100 Ω 0 Ω	-200.20	$26.10 \text{ m}\Omega$	200.20	86 μΩ
1 kΩ 0 Ω	-202.0	$25.9~\text{m}\Omega$	202.0	$0.29~\mathrm{m}\Omega$
10 kΩ 0 Ω	-0.220	0.025 Ω	0.220	$4.1~\text{m}\Omega$
100 kΩ 0 Ω	-0.60	0.01 Ω	0.60	$15~\text{m}\Omega$
1 M $\Omega$ 0 $\Omega$	-4.2	0.1 Ω	4.2	0.14 Ω

DC VOLTAGE GAIN PASSED

TEST COND	ITIONS	MINIMUM	MEASURED	MAXIMUM	<u>UNCERT.</u>
Range	Input				
DC Voltage	Channel1	-			
100 mV 1 V 10 V 100 V	100 mV 1 V 10 V 100 V	99.99560 0.9999610 9.999660 99.99600	100.00010 mV 1.0000001 V 10.000001 V 100.00093 V	100.00440 1.0000390 10.000340 100.00400	1.2 μV 5.8 μV 38 μV 0.56 mV
DC Voltage	Channel2				
100 mV 1 V 10 V	100 mV 1 V 10 V	99.99560 0.9999610 9.999660	100.00108 mV 1.0000013 V 10.000001 V	100.00440 1.0000390 10.000340	1.2 μV 5.8 μV 38 μV
DC Low-Vol	tage Char	nnel1			
1 mV 10 mV	1 mV 10 mV	0.9999300 9.999470	1.0000185 mV 9.999958 mV	1.0000700 10.000530	16 nV 0.11 μV
DC Low-Voltage Channel2					
1 mV 10 mV	1 mV 10 mV	0.9999300 9.999470	1.0000040 mV 9.999951 mV	1.0000700	15 nV 0.12 μV

OHMS GAIN PASSED

TEST COND.	<u>MINIMUM</u>	MEASURED	<u>MAXIMUM</u>	UNCERT.
D (01 ) T	. (01)			

Range (Ohm) Input (Ohm)

OHMS GAIN CONTINUED

TEST	COND.	MINIMUM	MEASURED	MAXIMUM	UNCERT.
4-Wi	re Ohms				
1 100 100 1k 10k 100k	1 10 100 1k 10k 10k	0.9999280 9.999380 99.99380 0.9999380 9.999380 99.99360 0.9999260	$0.99999992 \Omega$ $9.999988 \Omega$ $99.99971 \Omega$ $0.9999997 k\Omega$ $9.999988 k\Omega$ $100.00008 k\Omega$ $0.9999957 M\Omega$	1.0000720 10.000620 100.00620 1.0000620 10.000620 100.00640 1.0000740	$\begin{array}{c} 16 \ \mu\Omega \\ 0.14 \ \text{m}\Omega \\ 0.98 \ \text{m}\Omega \\ 7.8 \ \text{m}\Omega \\ 77 \ \text{m}\Omega \\ 1.0 \ \Omega \\ 18 \ \Omega \end{array}$
Low I	Power O	hms			
1 100 100 1k 10k 100k	1 10 100 1k 10k 10k	0.9999280 9.999380 99.99380 0.9999380 9.999360 99.99250 0.9999260	0.9999986 Ω 9.999986 Ω 99.99961 Ω 1.0000000 kΩ 9.999981 kΩ 100.00019 kΩ 0.9999958 MΩ	1.0000720 10.000620 100.00620 1.0000620 10.000640 100.00750 1.0000740	$\begin{array}{c} 16 \ \mu\Omega \\ 0.14 \ \text{m}\Omega \\ 0.97 \ \text{m}\Omega \\ 7.8 \ \text{m}\Omega \\ 77 \ \text{m}\Omega \\ 1.0 \ \Omega \\ 18 \ \Omega \end{array}$
Volta	age Lim	ited Ohms			
10 100	10 100	9.999280 99.99280	9.999970 Ω 99.99996 Ω		$\begin{array}{ccc} \text{0.14} & \text{m}\Omega \\ \text{0.97} & \text{m}\Omega \end{array}$